

# UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/664,783	09/16/2003	Hui Wang	495152000610	4793
7590 05/26/2005			EXAMINER	
Peter J. Yim			ESTRADA, MICHELLE	
Morrison & Foerster LLP 425 Market Street			ART UNIT	PAPER NUMBER
San Francisco, CA 94105-2482			2823	
			DATE MAILED: 05/26/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
	10/664,783	WANG ET AL.	/ m			
Office Action Summary	Examiner	Art Unit				
	Michelle Estrada	2823				
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the c	orrespondence ad	idress			
A SHORTENED STATUTORY PERIOD FOR REPL' THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a repl If NO period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be tim y within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONEI	nely filed s will be considered time the mailing date of this c O (35 U.S.C. § 133).	ly. communication.			
Status						
1) Responsive to communication(s) filed on 16 M	larch 2005.					
2a)⊠ This action is <b>FINAL</b> . 2b)□ This	action is non-final.					
3) Since this application is in condition for alloward closed in accordance with the practice under E			e merits is			
Disposition of Claims						
4) ☐ Claim(s) <u>11-60</u> is/are pending in the application 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) <u>31-43</u> is/are allowed.  6) ☐ Claim(s) <u>11,15,16,21-24,28-30,44,47,48,52-55</u> 7) ☐ Claim(s) <u>12-14,17-20,25-27,45,46,49-51,56 ard</u> 8) ☐ Claim(s) are subject to restriction and/o	wn from consideration.  5 and 58-60 is/are rejected.  10 57 is/are objected to.		·			
Application Papers						
9) The specification is objected to by the Examine	er.					
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.						
Applicant may not request that any objection to the	drawing(s) be held in abeyance. See	37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correct  11) The oath or declaration is objected to by the Ex			• •			
Priority under 35 U.S.C. § 119		·				
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Application fity documents have been received u (PCT Rule 17.2(a)).	on No ed in this National	Stage			
	•					
Attachment(s)  Notice of References Cited (PTO-892)	4) Interview Summary	(PTO-413)				
2) Notice of References Cited (F10-692) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail Da	ite				
B) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	5) Notice of Informal P 6) Other:	atent Application (PT0	O-152)			

Art Unit: 2823

#### **DETAILED ACTION**

## Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 11, 15, 24 and 29 are rejected under 35 U.S.C. 102(e) as being anticipated by Reid (6,653,226).

With respect to claim 11, Reid discloses a dielectric layer (103) formed on a semiconductor wafer (101) having a recessed area and a non-recessed area (See Fig. 1A); a plurality of dummy structures formed within the recessed area, wherein the dummy structures are inactive areas configured to increase the planarity of a metal layer (105) subsequently formed on the dielectric layer; a metal layer (105) formed to fill the recessed area and cover the non-recessed area and the plurality of dummy structures (See Fig. 1A), wherein the metal layer is electropolished to expose the non-recessed area (See Fig. 1B) (Col. 1, lines 50-57).

With respect to claim 15, Reid discloses wherein the metal layer is formed by depositing the metal layer (Col. 1, lines 54-55).

Art Unit: 2823

With respect to claim 24, Reid discloses wherein the recessed area is a wide

trnch configured to form an interconnection when filled with the metal layer (Col. 1, lines

15-16).

With respect to claim 29, Reid discloses wherein the plurality of dummy

structures includes the same material as the dielectric layer (Col. 1, lines 50-52).

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all

obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the

invention was made to a person having ordinary skill in the art to which said subject matter pertains.

Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of

the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of

the various claims was commonly owned at the time any inventions covered therein

were made absent any evidence to the contrary. Applicant is advised of the obligation

under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was

not commonly owned at the time a later invention was made in order for the examiner to

consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g)

prior art under 35 U.S.C. 103(a).

Art Unit: 2823

Claims 16, 21-23, 28, 44, 47, 48, 52-55, 58, 59 and 60 are rejected under 35 U.S.C. 103(a) as being unpatentable over Reid as applied to claims 11, 15, 24 and 29 above, and further in view of Cox (6,383,917).

Reid does not disclose wherein the metal layer is formed by electroplating the metal layer; the structure further comprising a barrier layer formed on the dielectric layer before forming the metal layer; a cover layer formed on the semiconductor wafer after electropolishing the metal layer; where the metal layer is copper.

With respect to claim 16, Cox discloses forming a metal layer (105) by electroplating (Col. 3, lines 58-60).

With respect to claim 21, Cox discloses further comprising a barrier layer (104) formed on the dielectric layer (103) before forming the metal layer (Col. 3, lines 19-21).

With respect to claim 22, Cox discloses further comprising a seed layer formed on the dielectric layer before forming the metal (Col. 3, lines 58-60).

With respect to claim 23, Cox discloses a cover layer (107/109) formed on the semiconductor wafer after electropolishing the metal layer.

With respect to claim 28, Cox discloses wherein the metal layer (105) is copper (Col. 3, lines 35-43).

With respect to claim 30, Cox discloses wherein the plurality of dummy structures includes a metal (Col. 4, lines 48-60).

It would have been within the scope of one of ordinary skill in the art to combine the teachings of Reid and Cox to enable the process of Reid to be performed according to the process of Cox because electroplating is inexpensive, fast and effective for thick

Art Unit: 2823

layers, forming a barrier layer in Reid will prevent diffusion of the metal layer, forming a seed layer is typically done when performing electroplating, forming a cover layer will provide protection to the structure, and the formation of dummy metal regions to the structure increase the surface area of the conductive material thus optimizing the process account for these changes in local fields, which could affect the uniformity of the etch rate.

With respect to claim 44, Reid does not disclose wherein the metal layer is overpolished to allow the non-recessed area to protrude past a surface of the metal layer in the recessed area. Cox discloses wherein the metal layer (105) is overpolished to allow the non-recessed area to protrude past a surface of the metal layer in the recessed area (See Fig. 1c and Col. 4, lines 1-14).

It would have been within the scope of one of ordinary skill in the art to combine the teachings of Reid and Cox to enable the electropolishing of Reid to be performed according to the teachings of Cox because the overpolishing enables production of an integrated circuit that maintains the strength characteristics imparted by the dielectric layer.

With respect to claim 47, Reid discloses wherein the metal layer is formed by depositing the metal layer (Col. 1, lines 54-55).

With respect to claim 48, Cox discloses forming a metal layer (105) by electroplating (Col. 3, lines 58-60).

With respect to claim 52, Cox discloses further comprising a barrier layer (104) formed on the dielectric layer (103) before forming the metal layer (Col. 3, lines 19-21).

Art Unit: 2823

With respect to claim 53, Cox discloses further comprising a seed layer formed on the dielectric layer before forming the metal (Col. 3, lines 58-60).

With respect to claim 54, Cox discloses a cover layer (107/109) formed on the semiconductor wafer after electropolishing the metal layer.

With respect to claim 55, Reid discloses wherein the recessed area is a wide trench configured to form an interconnection when filled with the metal layer (Col. 1, lines 15-16).

With respect to claim 58, Cox discloses wherein the metal layer (105) is copper (Col. 3, lines 35-43).

With respect to claim 59, Reid discloses wherein the plurality of dummy structures includes the same material as the dielectric layer (Col. 1, lines 50-52).

With respect to claim 60, Cox discloses wherein the plurality of dummy structures includes a metal (Col. 4, lines 48-60).

## Allowable Subject Matter

Claims 12-14, 17-20, 25-27, 45, 46, 49-51, 56 and 57 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is a statement of reasons for the indication of allowable subject matter: there is no disclosure in the prior art, either alone or in combination of the limitations recited in claims 12-14, 17-20, 25-27, 45, 46, 49-51, 56 and 57.

Art Unit: 2823

Claims 31-43 are allowed.

The following is an examiner's statement of reasons for allowance: With there is no disclosure in the prior art of electropolishing the barrier layer deposited on the non-recessed area, and wherein the exposed barrier layer is removed at a first rate and the non-recessed area of the dielectric layer is removed at a second rate.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

### Response to Arguments

Applicant's arguments filed 3/16/05 have been fully considered but they are not persuasive. Applicant argues that features 107 are not analogous to the dummy structures recited in claim 11. However, in the rejection mailed 12/16/04, the Examiner referred to structures 103 as the dummy structures formed in the recessed area 107/109.

#### Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within

TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Michelle Estrada whose telephone number is 571-272-1858. The examiner can normally be reached on Monday through Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Olik Chaudhuri can be reached on 571-272-1855. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 571-272-2800.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

Art Unit: 2823

you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

George Fourson
Primary Examiner
Art Unit 2823

Page 9

May 17, 2005